

FDD6680AS

30V N-Channel PowerTrench® SyncFET[™] General Description

The FDD6680AS is designed to replace a single MOSFET and Schottky diode in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low $R_{\rm DS(ON)}$ and low gate charge. The FDD6680AS includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology. The performance of the FDD6680AS as the low-side switch in a synchronous rectifier is indistinguishable from the performance of the FDD6680A in parallel with a Schottky diode.

Applications

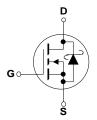
- DC/DC converter
- Low side notebook

Features

- 55 A, 30 V $R_{DS(ON)}$ max= 10.5 m Ω @ V_{GS} = 10 V $R_{DS(ON)}$ max= 13.0 m Ω @ V_{GS} = 4.5 V
- Includes SyncFET Schottky body diode
- Low gate charge (21nC typical)
- High performance trench technology for extremely low R_{DS(ON)}
- · High power and current handling capability

G D

TO-252



Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Paramete	r	Ratings	Unit s
V _{DSS}	Drain-Source Voltage		30	V
V _{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current - Continuous	(Note 3)	55	Α
	– Pulsed	(Note 1a)	100	
P _D	Power Dissipation	(Note 1)	60	W
		(Note 1a)	3.1	
		(Note 1b)	1.3	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		−55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	2.1	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1b)	96	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDD6680AS	FDD6680AS	13"	16mm	2500 units
FDD6680AS	FDD6680AS_NL (Note 4)	13"	16mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	urce Avalanche Ratings (No	te 2)			I	1
W _{DSS}	Drain-Source Avalanche Energy	Single Pulse, $V_{DD} = 15 \text{ V}$, $I_D=13.5\text{A}$		54	205	mJ
I _{AR}	Drain-Source Avalanche Current				13.5	Α
Off Char	acteristics			•	•	
BV _{DSS}	Drain–Source Breakdown Voltage	V _{GS} = 0 V, I _D = 1 mA	30			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 1 mA, Referenced to 25°C		29		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			500	μА
I _{GSS}	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			±100	nA
On Char	acteristics (Note 2)				•	
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 1 \text{ mA}$	1	1.4	3	V
$\Delta V_{GS(th)} \ \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I _D = 1 mA, Referenced to 25°C		-3		mV/°(
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V}, \qquad I_{D} = 12.5 \text{ A}$		8.6	10.5	mΩ
	On-Resistance	$V_{GS} = 4.5 \text{ V}, \qquad I_D = 10 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 12.5 \text{A}, T_J = 125 ^{\circ} \text{C}$		10.3 12.5	13.0 16.0	
I _{D(on)}	On–State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$	50	1 - 1 - 1		Α
9rs	Forward Transconductance	$V_{DS} = 15 \text{ V}, \qquad I_D = 12.5 \text{ A}$		44		S
	Characteristics	, -				
		$V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		4000		
C _{iss}	Input Capacitance	f = 1.0 MHz		1200		pF
Coss	Output Capacitance			350		pF
C _{rss}	Reverse Transfer Capacitance			120		pF
R _G	Gate Resistance	$V_{GS} = 15 \text{ mV}, f = 1.0 \text{ MHz}$		1.6		Ω
Switchin	g Characteristics (Note 2)			T	Г	
d(on)	Turn-On Delay Time			10	20	ns
r	Turn-On Rise Time	$V_{DD} = 15 \text{ V}, \qquad I_{D} = 1 \text{ A},$		6	12	ns
d(off)	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		28	45	ns
f	Turn-Off Fall Time			12	22	ns
d(on)	Turn-On Delay Time			14	25	ns
r	Turn-On Rise Time	$V_{DD} = 15 \text{ V}, \qquad I_{D} = 1 \text{ A},$		13	23	ns
d(off)	Turn-Off Delay Time	$V_{GS} = 4.5 \text{ V}, \qquad R_{GEN} = 6 \Omega$		20	32	ns
t _f	Turn–Off Fall Time			11	20	ns
$Q_{g(TOT)}$	Total Gate Charge at Vgs=10V			21	29	nC
Q _g	Total Gate Charge at Vgs=5V	$V_{DD} = 15 \text{ V}, I_D = 12.5 \text{ A}$		11	15	nC
Q _{gs}	Gate-Source Charge	-		3		nC
Q_{gd}	Gate-Drain Charge			4		nC
Drain-So	ource Diode Characteristics			1	1	
ls	Maximum Continuous Drain-Source				4.4	Α
V _{SD}	Drain–Source Diode Forward Voltage	$ \begin{array}{cccccccccccccccccccccccccccccccccccc$		0.5 0.6	0.7	V
t _{rr}	Diode Reverse Recovery Time	$I_F = 12.5A,$ $d_{iF}/d_t = 300 \text{ A/}\mu\text{s}$ (Note 3)		17		nS
Q _{rr}	Diode Reverse Recovery Charge	1		11		nC

Electrical Characteristics

T_A = 25°C unless otherwise noted

Notes

1. $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) $R_{\theta JA} = 40$ °C/W when mounted on a 1in^2 pad of 2 oz copper



b) $R_{\theta JA} = 96^{\circ}\text{C/W}$ when mounted on a minimum pad.

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%

3. Maximum current is calculated as: $\sqrt{\frac{P_D}{R_{DS(ON}}}$

where P_D is maximum power dissipation at $T_C = 25^{\circ}C$ and $R_{DS(on)}$ is at $T_{J(max)}$ and $V_{GS} = 10V$. Package current limitation is 21A

 $\textbf{4.} \ \ \mathsf{FDD6680AS_NL} \ \text{is a lead free product.} \ \ \mathsf{The} \ \mathsf{FDD6680AS_NL} \ \mathsf{marking} \ \mathsf{will} \ \mathsf{appear} \ \mathsf{on} \ \mathsf{the} \ \mathsf{reel} \ \mathsf{label}.$

Typical Characteristics

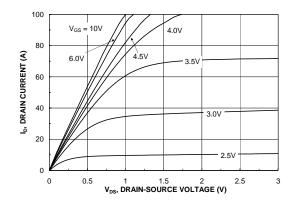


Figure 1. On-Region Characteristics.

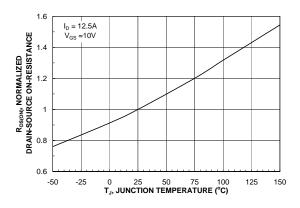


Figure 3. On-Resistance Variation with Temperature.

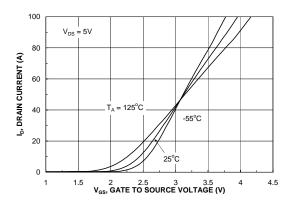


Figure 5. Transfer Characteristics.

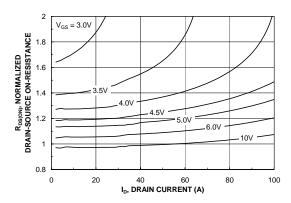


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

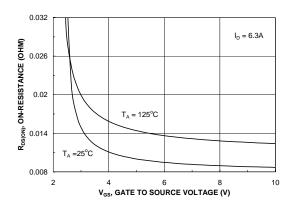


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

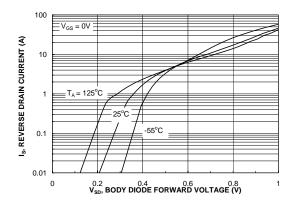
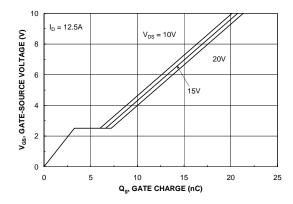


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics (continued)



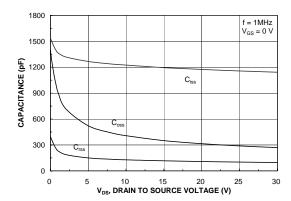
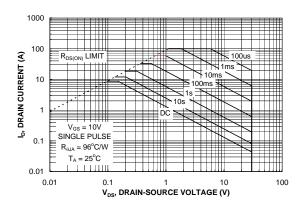


Figure 7. Gate Charge Characteristics.





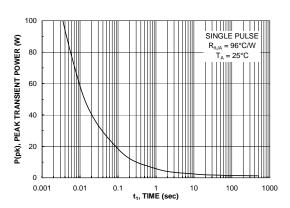


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

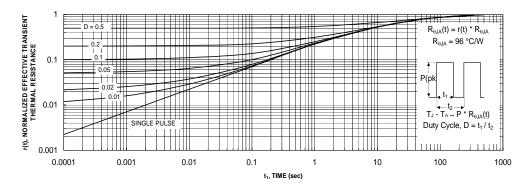


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

Typical Characteristics (continued)

SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 shows the reverse recovery characteristic of the FDD6680AS.

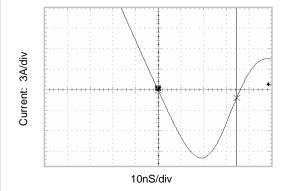


Figure 12. FDD6680AS SyncFET body diode reverse recovery characteris

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDD6680).

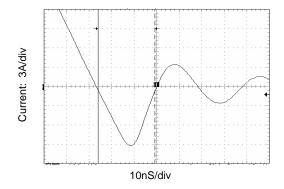


Figure 13. Non-SyncFET (FDD6680) body diode reverse recovery characteristic.

Schottky barrie diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

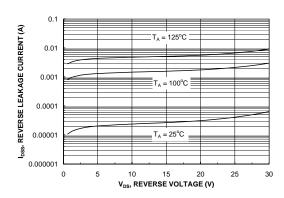
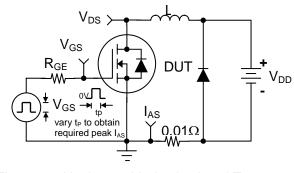


Figure 14. SyncFET body diode reverse leakage versus drain-source voltage and temperature.

Typical Characteristics



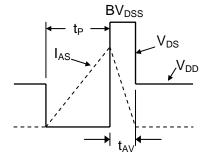
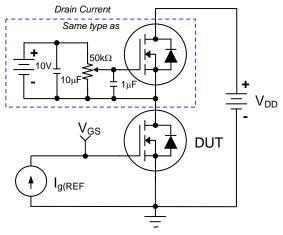


Figure 12. Unclamped Inductive Load Test Circuit

Figure 13. Unclamped Inductive Waveforms



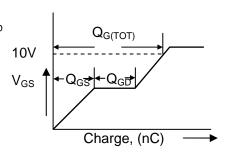
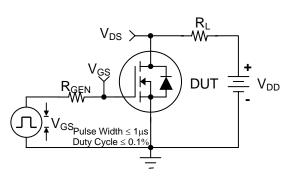


Figure 14. Gate Charge Test Circuit

Figure 15. Gate Charge Waveform



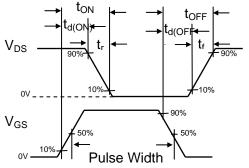


Figure 16. Switching Time Test Circuit

Figure 17. Switching Time Waveforms

TRADEMARKS

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

$ACEx^{TM}$	FAST®	IntelliMAX™	POPTM	SPM™
ActiveArray™	FASTr™	ISOPLANAR™	Power247™	Stealth™
Bottomless™	FPS™	LittleFET™	PowerEdge™	SuperFET™
CoolFET™	FRFET™	MICROCOUPLER™	PowerSaver™	SuperSOT™-3
CROSSVOLT™	GlobalOptoisolator™	MicroFET™	PowerTrench®	SuperSOT™-6
DOME™	GTO™ .	MicroPak™	QFET®	SuperSOT™-8
EcoSPARK™	HiSeC™	MICROWIRE™	QS™	SyncFET™
E ² CMOS TM	I ² C TM	MSX TM	QT Optoelectronics™	TinyLogic [®]
EnSigna™	i-Lo™	MSXPro™	Quiet Series™	TINYOPTO™
FACT™	ImpliedDisconnect™	OCX^{TM}	RapidConfigure™	TruTranslation™
FACT Quiet Series [™]		OCXPro™	RapidConnect™	UHC™
Across the boar	d. Around the world.™	OPTOLOGIC®	μSerDes™	UltraFET [®]
The Power Franchise®		OPTOPLANAR™	SILENT SWITCHER®	UniFET™
Programmable Active Droop™		PACMAN™	SMART START™	VCX TM

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the
- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.

Rev. I15